CALL FOR PAPERS

8th International Conference on Quality Control by Artificial Vision

SPIE Europe is a cooperating organization

QCAV'2007

Le Creusot, France, May 23-25, 2007

http://www.qcav.org

Organizing Committee

General Chair
David FOFI
Le2i – IUT Le Creusot, University of Burgundy, France

Members
Hakim ATMANI
Olivier AUBRETON
Alain DIOU
Eric FAUVET
Mathias FERRATON
Yohan FOUGEROLLE
Patrick GORRIA
Olivier LALIGANT
Bernard LAMALLE
Jérome LANDRE
Alexandra LATHUILIERE
Dominique LAURENT
Magali LEMAITRE
Lew F.C. LEW YAN VOON
Benjamin LORIOT
Fabrice MERIAUDEAU
Thierry MOLINIER
Olivier MOREL
Nathalie RAVEY
Ralph SEULIN
Christophe STOLZ
Pierre SUZEAU
Frédéric TRUCHETET

International Scientific Committee

General Chair
Philippe BOLON
University of Savoie, France

General co-chair
Kenneth TOBIN, Jr.
Oak Ridge National Laboratory, USA

Members
Mongi ABIDI
University of Tennessee, USA
Pierre BOULANGER
University of Alberta, Canada
Jean-Marc CHASSERY
Grenoble National Polytechnic Institute, France
Carlos FERNANDEZ
Polytechnic University of Cartagena, Spain
Luciano FONTOURA DA COSTA
Institute of Physics of Sao Carlos, Brazil
Christian GERMAIN
ENITA, Bordeaux, France
Shaun GLEASON
Oak Ridge National Laboratory, USA
Patrick GORRIA
University of Burgundy, France
Seija HATA
Kagawa University, Japan
Martin HUNT
nLine Corporation, USA
Akira ISHII
Kagawa University, Japan
Valérie KAFTANDJIAN
National Institute od Applied Sciences, France
Majdi KHOUDEIR
University of Poitiers, France
Hiroyasu KOSHIMIZU
Chukyo University, Japan
Lew F.C. LEW YAN VOON
University of Burgundy, France
Xavier MALDAGUE
Laval University, Québec, Canada
Timothy McINTYRE
Oak Ridge National Laboratory, USA
Fabrice MERIAUDEAU
University of Burgundy, France
Vittorio MURINO
University of Verona, Italy
Tim NEWMAN
University of Alabama, USA
Kurt NIEL
University of Applied Sciences, Wels, Austria
Heinrich NIEMANN
University of Erlangen, Germany
Fathallah NOUBOUD
University of Québec, Trois-Rivières, Canada
Christophe ODET
National Institute of Applied Sciences, France
Paul O'LEARY
Christian Doppler Laboratories, Austria
Jean-Charles PINOLI
Ecole des Mines de Saint-Etienne, France
Françoise PRETEUX
National Institute of Telecommunications, France
Jeffery PRICE
Oak Ridge National Laboratory, USA
Philippe SALEMBIER
Polytechnic University of Catalonia, Spain
Hamed SARI-SARRAF
Texas Tech University
Olli SILVEN
University of Oulu, Finland
Vladimir SMUTNY
Czech Technical University, Czech Republic
James SOLINSKY
Pacific Northwest National Laboratory, USA
Rin-Ichiro TANIGUCHI
Kyushu University, Japan
Frédéric TRUCHETET
University of Burgundy, France
Okitoshi TSUNODA
IBM Japan, Japan
Pascal VASSEUR
University of Picardie Jules Verne, France
Kazuhiko YAMAMOTO
Gifu University, Japan
Hongbin ZHA
Center for Information Science, Beijing University, China

Scope. The objective of the QCAV'2007 conference is to provide a forum for researchers, industry, and users of vision systems to present and discuss the state-of-the-art in machine vision and image processing techniques, with an emphasis on industrial applications for quality control of manufactured products. The presentations will include contributed papers, poster sessions and invited speakers for state-of the-art talks in specialized subjects related to the conference topics. Papers describing original work concerning the theoretical and experimental aspects of image processing are invited. The Scientific Committee invites authors to submit original unpublished paper proposals which present industrial quality control applications. For the first time, a special **video session** will be organized. Authors are encouraged to submit to this video track.

THE PROCEEDINGS VOLUME WILL BE PUBLISHED BY **SPIE** AND BE AVAILABLE **ONSITE**.

A SELECTION OF THE BEST PAPERS WILL BE PUBLISHED IN A SPECIAL ISSUE OF THE **JOURNAL OF ELECTRONIC IMAGING** (CO-EDITED BY **SPIE** AND **IS&T**).

A SELECTION OF THE BEST PAPERS SUBMITTED TO THE **VIDEO SESSION** WILL BE PUBLISHED IN A SPECIAL ISSUE OF THE **ELECTRONIC LETTERS ON COMPUTER VISION AND IMAGE ANALYSIS** (EDITED BY **CVC PRESS**).

Topics & methods. Papers are invited that describe novel theoretical, experimental, and applied work in image processing and computer vision for industrial quality control through improved metrology, inspection, and process characterization. Papers are solicited from, but not limited to, the following categories:

- Vision Sensor Development and Integration
- Optical, Electron, X-ray, Ultrasound and other Imaging Modalities
- Non-destructive Testing and Metrology
- Image Processing, Transforms, Segmentation and Pattern Recognition
- Image Data Management, Analysis and Interpretation
- Process Automation, Characterization and Control
- Remote Diagnostics

There are many industries that are benefiting from artificial vision today. Papers are particularly encouraged from, but not limited to, the following industries:

Agriculture
Aluminium
Biomedical
Chemicals
Food
Forest Products
Glass
Metal Casting
Mining
Petroleum
Pharmaceuticals
Semiconductors
Steel
Textiles

Submission procedure. Prospective authors must submit an extended summary of approximately 2,000 words (not including references) in English. Summaries must be single column and formatted to fit 8.5 in. x 11 in. page size (or A4 format). Electronic submissions must be in Adobe PDF format only. Authors can choose either **oral**, **poster** or **video** presentation.

Video session. Video segments of between 5 to 15 minutes in length illustrating new and significant results are requested for the special video sessions. Videos must be accompanied by an extended abstract and should be submitted following the instructions on the web.

IMPORTANT DATES

Summary submission deadline	**November 9, 2006**
Notification of acceptance	**December 14, 2006**
Final manuscript due date	**February 2, 2007**
Conference dates	**May 23-25, 2007**